

1N4448

FEATURES

- Silicon Epitaxial Planar Diode
- · Fast switching diode
- This diode is also available in other case styles including: the SOD-123 case with the type designation 1N4448W, the MiniMELF case with the type designation LL4448, and the SOT23 case with the type designation

MECHANICAL DATA

• Case: DO-35

• Weight: apprax: 0.13gram

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

• Ratings at 25°C ambient temperature unless otherwise specified

	Symbol	Value	Unit	
Reverse Voltage	V _R	75	V	
Peak Reverse Voltage	V _{RM}	100	V	
Rectified Current (Average) Half Wave Rectification with Resist. Load at T _{amb} = 25 °C and f ≥ 50 Hz	I ₀	150 ¹⁾	mA	
Surge Forward Current at t < 1 s and T _j = 25 °C	I _{FSM}	500	mA	
Power Dissipation at T _{amb} = 25 °C	P _{tot}	500 ¹⁾	mW	
Junction Temperature	T _j	175	°C	
Storage Temperature Range	T _S	-65 to +175	°C	

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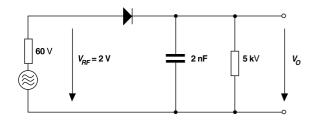


ELECTRICAL CHARACTERISTICS

Ratings at 25 °C ambient temperature unless otherwise specified

	Symbol	Min.	Тур.	Max.	Unit
Forward Voltage at I _F = 5 mA at I _F = 10 mA	V _F V _F	0.62	_ _	0.72 1	V
Leakage Current at $V_R = 20 \text{ V}$ at $V_R = 75 \text{ V}$ at $V_R = 20 \text{ V}$, $V_j = 150 \text{ °C}$	I _R I _R I _R	_ _ _	- - -	25 5 50	nA μA μA
Reverse Breakdown Voltage tested with 100 μA Pulses	V _{(BR)R}	100	_	_	V
Capacitance at $V_F = V_R = 0 V$	C _{tot}	-	-	4	pF
Reverse Recovery Time from I_F = 10 mA to I_R = 1 mA, V_R = 6 V, R_L = 100 Ω	t _{rr}	_	-	4	ns
Thermal Resistance Junction to Ambient Air	R _{thJA}	_	_	3501)	K/W
Recification Efficiency at $f = 100 \text{ MHz}$, $V_{RF} = 2 \text{ V}$	ην	0.45	_	_	_

¹⁾ Valid provided that leads at a distance of 8 mm from case are kept at ambient temperature.

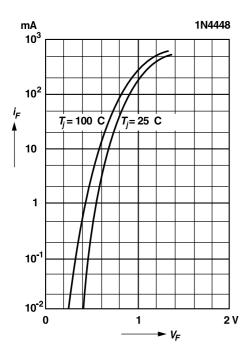


Rectification Efficiency Measurement Circuit



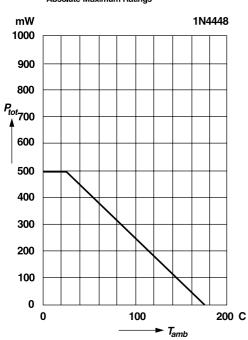
RATINGS AND CHARACTERISTIC CURVES 1N4448

Forward characteristics

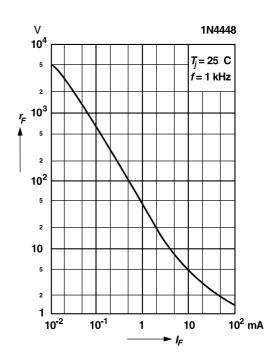


Admissible power dissipation versus ambient temperature

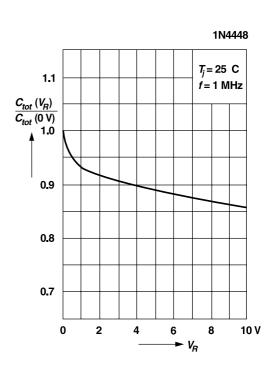
For conditions, see footnote in table "Absolute Maximum Ratings"



Dynamic forward resistance versus forward current



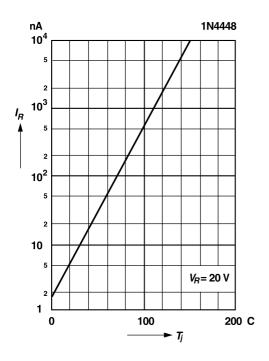
Relative capacitance versus reverse voltage





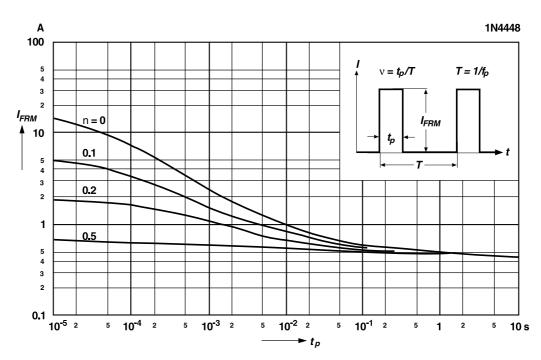
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Leakage current versus junction temperature



Admissible repetitive peak forward current versus pulse duration

For conditions, see footnote in table "Absolute Maximum Ratings"



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